

IN THE SPECIFICATION:

Please replace paragraph [0061] with the following amended paragraph:

[0061] The average voltage and the difference between the maximum and minimum voltage of the substrates processed according to examples 1-3 and comparative example 1 were also measured to detect large voltages and voltage differences across substrates that may contribute to plasma-induced damage. The average voltage of a substrate processed according to comparative example 1 was [-0.105] -0.105 V, and the voltage difference across the substrate was 2.14V. The average voltage of a substrate processed according to example 1 was 0.061 V, and the voltage difference across the substrate was 0.73 V. The average voltage of a substrate processed according to example 2 was 0.061 V, and the voltage difference across the substrate was 0.73 V. The average voltage of a substrate processed according to example 3 was 0.054 V, and the voltage difference across the substrate was 0.57 V. Thus, the processes described herein reduced the average voltage of a substrate and the voltage difference across the substrate relative to comparative example 1.

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